Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/817,273	NISHI, TAKASHI	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED					
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	DATE	EXMR
Reviewed Parent Application 09/914542 (US PAT. 6,725,528)	1/6/2006	PK
Text Search EAST/ NPL (IEEE)	1/9/2006	PK
Updated Text Search EAST/ PGPub	5/2/2006	PK